

Machine learning clustering techniques for selective mitigation of critical design features

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Machine learning to tackle the challenges of transient and soft errors in complex circuits

Lange, Thomas; **Balakrishnan, Aneesh**; Glorieux, Maximilien; Alexandrescu, Dan; Sterpone, Luca 2019 IEEE 25th International Symposium on On-Line Testing and Robust System Design (IOLTS), 1-3 July 2019, Greece 2019 / p. 7-14 : ill <https://doi.org/10.1109/IOLTS.2019.8854423>

A new FPGA-based detection method for spurious variations in PCBA power distribution network

Odintsov, Sergei; Bozzoli, Ludovica; De Sio, Corrado; Sterpone, Luca; **Jutman, Artur** 2019 22nd International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS), Cluj-Napoca, Romania : proceedings 2019 / 6 p. : ill <https://doi.org/10.1109/DDECS.2019.8724662>

On the estimation of complex circuits functional failure rate by machine learning techniques

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